

Selecting Sketches for Similarity Search

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Similarity Search

- **Field:** searching for similar objects
- *Queries by example*
 - The goal is to efficiently find the most similar objects to a given **query object**



- Wide range of applications
 - information retrieval, recommender systems, searching in biometrics, event detection, ...

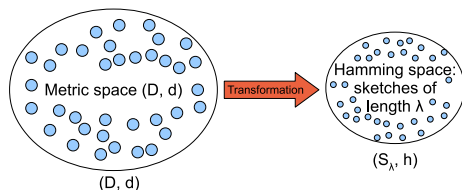
- We consider similarity modelled by the **metric space** (D, d)
 - D – domain of objects – original objects or their descriptive features
 - $d : D \times D \mapsto \mathbb{R}^+$ – distance function
 - the bigger the value $d(o_1, o_2)$, the less similar objects o_1, o_2
- Dataset $X \subseteq D$
- Having a query object $q \in D$, the goal is to efficiently find the most similar objects $o \in X$ to q

- Challenges:
 - Dataset X usually contains a lot of objects
 - Objects $o \in X$ are often big
 - Similarity function d may be complex and expensive

- We have limited computational power
- Queries have to be evaluated fast

Bit String Sketches

- Successful family of techniques to mitigate these problems: **transformation** of the metric space (D, d) to the **Hamming space**
 - **sketch** $sk(o)$ of object $o \in X$ is **bit string of length λ**
 - $sk : D \mapsto \{0, 1\}^\lambda$: *sketching* (transformation) *technique*
- Sketches compared by the Hamming distance **approximate similarity relationships** between objects $o \in X$



- Sketches are **small** ($\lambda \approx 64 - 256$ bits)
- Evaluation of the **Hamming distance** is **efficient**

- Current state
 - many sketching techniques sk exist
 - each sketching technique is suitable for just some datasets
 - sketch length λ and all parameters of sk must be set, which requires an expert knowledge or complex testing

Our Objectives

- we provide a tool to efficiently estimate a quality of a sketching technique sk considering a given dataset

Testing Sketching Techniques

- **Established way of testing is expensive:**
 - select a sample set of X of a representative size
 - select a set of query objects $Q \subseteq D$
- and **compare precise query results**
 - k most similar objects $o \in X$ to each query $q \in Q$
- **with approximate** (and more efficient) query evaluation based on **sketch filtering**

- This comparison is made for each investigated sketching technique to select the best one

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 - select a set of query objects $Q \subseteq D$
- and compare precise query results
 - k most similar objects $o \in X$ to each query $q \in Q$
- with approximate (and more efficient) query evaluation based on sketch filtering
 - identify $c \geq k$ most similar sketches $sk(o)$ to $sk(q)$
 - access objects $o \in X$ that correspond to the most similar sketches (*candidate objects*) and evaluate distances $d(q, o)$
 - answer: k most similar candidate objects
- This comparison is made for each investigated sketching technique to select the best one

Pros and Cons of Established Testing

- This established testing:
 - is affected by a selection of query objects Q
 - dataset X and query set Q must be of **sufficient (big) size**
 - we usually use $|X| \geq 1,000,000$ objects
 - all sketches for each $o \in X$ and $q \in Q$ must be created
 - evaluation of **precise answers** for each query object $q \in Q$ must be performed (it is expensive)
 - quality of approximate evaluations is strongly influenced by the **number of selected candidate objects c**
 - selecting c with **no prior knowledge** of the sketching technique is difficult
 - therefore: **very expensive procedure with limited detachment**
 - + comparison of precise and approximate answer is intuitive and **easy to understand**

- We propose two **efficient methods** to estimate **quality of sketches** $sk(o)$, $o \in X$
 - i.e., their ability to approximate similarity relationships of objects $o \in X$
 - Both use just a very small sample set of data
- Both are based on **probabilistic analysis**

Pros and Cons of Our Methods

- Our methods

- + do not use **any query objects Q** (so are not affected by their selection)
- + small sample set of \approx **2,000 – 5,000 objects $o \in X$** is sufficient for our estimations
- all sketches $sk(o)$ for the sample set must be created
- + no need to expensively evaluate any **precise query answers**
- + no candidate set is used, so **no expert knowledge** or testing to set its size is required

- + therefore: **efficient methods, easy to use**
 - Examination of a set of sketches made by a given sketching technique sk requires **less than 1 minute**

- quality of sketching technique is expressed by an **abstract real number** with *no intuitive meaning*

Our Approach

- Let us have a sketching technique sk producing sketches of length λ and distance $x = d(o_1, o_2)$
- we model¹ probability $p(x, b)$ that the Hamming distance of sketches $sk(o_1), sk(o_2)$ is b for $0 \leq b \leq \lambda$, i.e. $h(sk(o_1), sk(o_2)) = b$

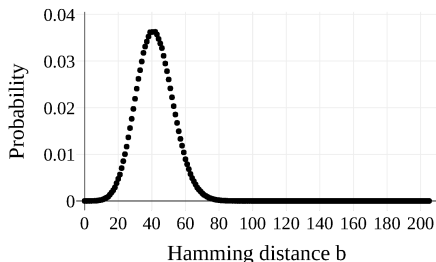


Figure: Example of probability function $p(x, b)$ for a given value x

¹details later

Projection of Two Distances x_1, x_2

- Consider **two distances** $x_1 < x_2$ and functions $p(x_1, b)$, $p(x_2, b)$

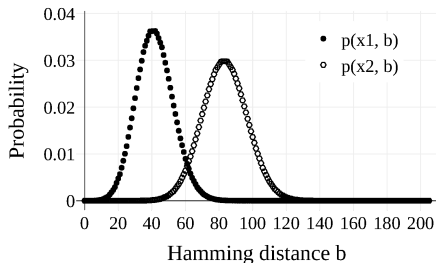


Figure: Functions $p(x_1, b)$, $p(x_2, b)$ for given values x_1, x_2

- Ideal case: sketching technique **preserve ordering of distances**
 - i.e. $x_1 < x_2 \implies h(sk(o_1), sk(o_2)) < h(sk(o_3), sk(o_4))$
- We evaluate **separation** of probability functions $p(x_1, b)$, $p(x_2, b)$

Separation of Projected Distances

- m_1, m_2 ... **means** of $p(x_1, b)$, $p(x_2, b)$
- s_1^2, s_2^2 ... **variances** of $p(x_1, b)$, $p(x_2, b)$

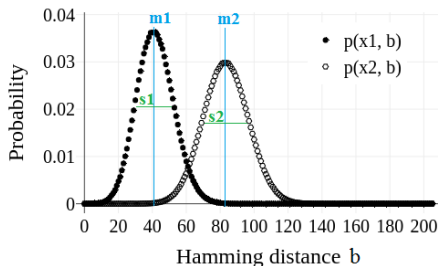


Figure: Functions $p(x_1, b)$, $p(x_2, b)$ for given values x_1, x_2

- **Separation** of functions²

$$sep_{sk}(x_1, x_2) = \frac{m_2 - m_1}{\sqrt{\frac{s_1^2 + s_2^2}{2}}}$$

²adopted formula

Quality of Sketching Technique

- Quality of a sketching technique sk :

We evaluate $sep_{sk}(x_1, x_2)$ over whole range $[0, \Gamma]$ of distances x_1, x_2 :

$$quality(sk) = \int_0^\Gamma \int_{x_1}^\Gamma sep_{sk}(x_1, x_2) \partial x_2 \partial x_1$$

Interpretation

Value $quality(sk)$ describes, how much a sketching technique sk distinguishes distances between objects $o \in X$, i.e. **quality of sk**

- Possible modifications:
 - (1) normalization by Γ^2
 - (2) similarity search: focus on separation of *small distances* (that are smaller than some t) from others

$$quality_{norm}(sk, t) = \frac{\int_0^t \int_{x_1}^\Gamma sep_{sk}(x_1, x_2) \partial x_2 \partial x_1}{\Gamma^2}$$

Approaches to model function $p(x, b)$

- **Details:** two approaches to model probability function $p(x, b)$
 - **Approach A** (*analytique*)
 - **Approach PM** (*partially measured*)
- Both approaches use
 - set of distances $d(o_1, o_2)$ and
 - corresponding Hamming distances on sketches $h(sk(o_1), sk(o_2))$to estimate **means m and variances s^2** of $p(x, b)$, and therefore $sep_{sk}(x_1, x_2)$:

$$sep_{sk}(x_1, x_2) = \frac{m_2 - m_1}{\sqrt{\frac{s_1^2 + s_2^2}{2}}}$$

Approach A

- **Approach A** models (complete) function $p(x, b)$
 - precomputed distances are investigated to get an average probability $p_i(x, 1)$ that **one bit** of sketches $sk(o_1)$ and $sk(o_2)$ is different
 - complete $p(x, b)$ is modelled by a composition of λ instances of $p_i(x, 1)$
 - **Approach A** reveals statistical properties of sketches that improve their quality
- **Approach PM**:
 - means and variances m and s^2 of $p(x, b)$ are **directly evaluated** using precomputed distances d and h
 - **Approach PM** does not reveal statistical properties of sketches that improve their quality

We experimentally verify **our estimators** by their comparison with **the established testing procedure**

- **4 different sketching techniques sk**
 - based on *generalized hyperplane partitioning (GHP50, GHP80)*, *ball partitioning (BP50)*, and *thresholding (THRR50)*
 - their detailed description is in the paper
- For each technique **4 different lengths λ** are examined (if possible)
 - 64, 128, 192, 256 bits
- **Two datasets** of size $|X| = 1,000,000$ vectors, each
 - real-valued vectors of length 4,096 (*DeCAF from neural network*)
 - real-valued vectors of length 128 (*SIFT: local visual image descriptors*)

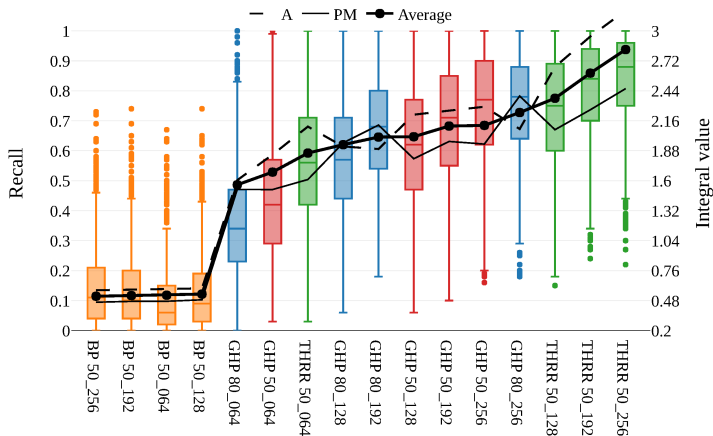
- **Established testing procedure:**
 - *the recall value*: size of intersection of the precise and approximate query answers
 - 1,000 queries q , search for 100 nearest neighbour
 - candidate set size: 2,000 objects (i.e. 0.2%)

- **Costs:**
 - Precise answers: up to **2 billion** $d(q, o)$ evaluations (brute force)
 - among other things, **6.5 billion** $d(o_1, o_2)$ evaluations to create **30** different sets of sketches

Experiments – Our Estimations

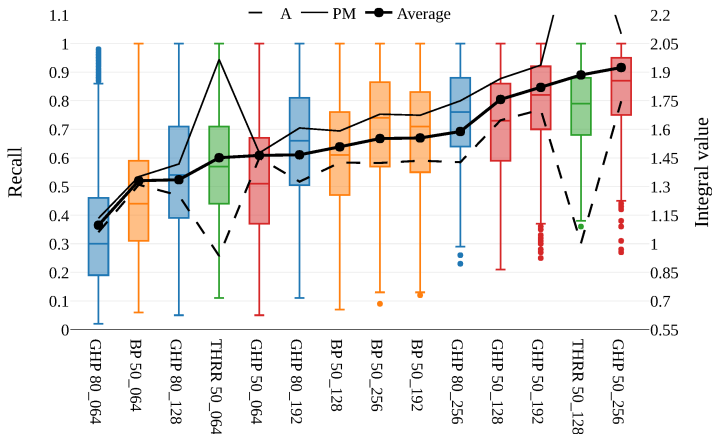
- Our estimators use **5,000 randomly selected objects** $o \in X$ and their sketches $sk(o)$ made by each investigated sketching technique
- We evaluate 2,000,000 distances $d(o_1, o_2)$ and corresponding $h(sk(o_1), sk(o_2))$ to get our **estimations**
- Estimation takes 30 – 50 seconds per set of sketches

Results – DeCAF dataset



- x-axis: sets of sketches, 3 last digits: sketch length λ , colours of box plots: principally different sketching techniques
- primary y-axis: the recall examined by expensive *established testing* (box plots)

Results – SIFT dataset



- x-axis: sets of sketches, **3 last digits**: sketch length λ , **colours of box plots**: principally different sketching techniques
- primary y-axis: the recall examined by expensive *established testing* (box plots)

Results – Correlations

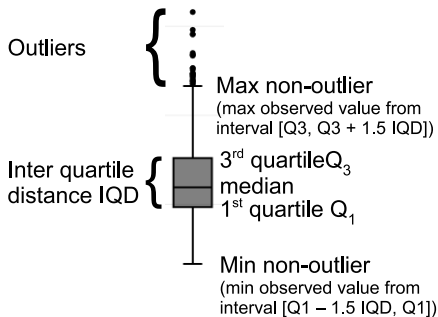
- Average of both estimations – **high quality results**
(possible since both estimations use the same scale)

Table: Correlations of quality estimations and measured medians of the recall

	Approach A	Approach PM	Average of estimations
DeCAF	+0.96	+0.97	+0.98
SIFT	+0.55	+0.74	+0.93

- Conclusions:
 - We proposed analytical tools to estimate **quality of binary sketches**
 - They use **very small sample of data**
 - They are **very efficient**

- The recall value (i.e. quality of sketch based filtering examined by the established approach) is expressed by box plots to show distribution of values among particular query objects $q \in Q$



Question in reviews: how about **scalability** of sketches:

- If sketches are not indexed³, just their *quality* matters
- Indexing of sketches is hard, in general, due to big Hamming distance to nearest neighbours
- *Indexability* of sketches made a given sketching technique *sk* strongly depends on a dataset
- We cannot make conclusions about the examined techniques based on testing on 2 datasets ...

³i.e. our case: sequential evaluation of (all) Hamming distances is considered